

<IGBT Modules>

CM400DU-24TH

HIGH POWER SWITCHING USE INSULATED TYPE



Collector-emitter voltage V_{CES} 1 2 0 0 V

Maximum junction temperature T_{vjmax} 1 7 5 °C

- dual switch (half-bridge)
- Copper base plate (Nickel-plating)
- •Tin-plating tab terminals
- •RoHS Directive compliant
- •UL Recognized under UL1557, File No. E323585

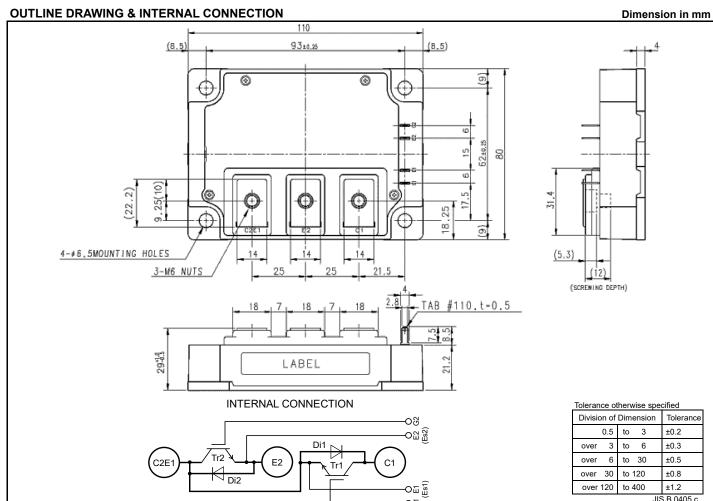
APPLICATION

Medical equipment, Welder, Power supply, etc.

OPTION (Below options are available.)

VcEsat selection for parallel connection

Publication Date: December 2020



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MAXIMUM RATINGS (T_{vj} =25 °C, unless otherwise specified)

Symbol	Item	Conditions	Rating	Unit
V _{CES}	Collector-emitter voltage	G-E short-circuited	1200	V
V _{GES}	Gate-emitter voltage	C-E short-circuited	± 20	V
Ic	Collector current	DC, T _C =25 °C (Note2, 4)	400	^
I _{CRM}	Collector current	Pulse, Repetitive (Note3)	800	Α
P _{tot}	Total power dissipation	T _C =25 °C (Note2, 4)	1970	W
I _E (Note1)	Funithan accompant	DC, Tc=25 °C (Note2)		۸
I _{ERM} (Note1)	Emitter current	Pulse, Repetitive (Note3)	800	A
V _{isol}	Isolation voltage	Terminals to base plate, RMS, f=60 Hz, AC 1 min	4000	V
T_{vjmax}	Maximum junction temperature	Instantaneous event (overload) (Note 8)	175	°C
T _{Cmax}	Maximum case temperature	(Note4, 8)	125	
T _{vjop}	Operating junction temperature	Continuous operation (under switching) (Note 8)	-40 ~ +150	°C
T _{stg}	Storage temperature	-	-40 ~ +125	

$\begin{tabular}{ll} ELECTRICAL CHARACTERISTICS (T_{vj}\ensuremath{=}25\ensuremath{\,^{\circ}}\ensuremath{C}, unless otherwise specified) \ensuremath{\line(T_{vj}\ensuremath{=}25\ensuremath{\,^{\circ}}\ensuremath{C}, unless otherwise specified) \ensuremath{\line(T_{vj}\ensuremath{=}25\ensuremath{\,^{\circ}}\ensuremath{C}\ensuremath{\line(T_{vj}\ensuremath{=}25\ensuremath{\,^{\circ}}\ensuremath{C}, unless otherwise specified) \ensuremath{\line(T_{vj}\ensuremath{=}25\ensuremath{\,^{\circ}}\ensuremath{\line(T_{vj}\ensuremath{=}25\ensuremath{\,^{\circ}}\ensuremath{\line(T_{vj}\ensuremath{}25\ensuremath{\,^{\circ}}\ensuremath{\line(T_{vj}\ensuremath{}25\ensuremath{\,^{\circ}}\ensuremath{\line(T_{vj}\ensuremath{\line(T$

Symbol	Item	Conditions			Limits		Unit
Symbol	item	Conditions		Min.	Тур.	Max.	Offic
I _{CES}	Collector-emitter cut-off current	$V_{CE}=V_{CES}$, G-E short-circuited $ \frac{T_{vj}=25 \text{ °C}}{T_{vj}=150 \text{ °C}} $	T _{vj} =25 °C	-	-	1.0	mA
ICES	Collector-entitler cut-off current				75.0	ША	
I _{GES}	Gate-emitter leakage current	V _{GE} =V _{GES} , C-E short-circuited		-	-	0.5	μA
$V_{GE(th)}$	Gate-emitter threshold voltage	I _C =40 mA, V _{CE} =10 V		5.40	6.00	6.60	V
.,		I _C =400 A, V _{GE} =15 V,	T _{vj} =25 °C	-	4.40	5.10	
V _{CEsat} (Terminal)		Refer to the figure of test circuit	T _{vj} =125 °C	-	4.50	-	V
(Terminal)	Callantan amittan antumation valtama	(Note5)	T _{vj} =150 °C	-	4.40	-	
	Collector-emitter saturation voltage	I _C =400 A,	T _{vj} =25 °C	-	4.35	5.05	
V _{CEsat}		V _{GE} =15 V,	T _{vj} =125 °C	-	4.45	-	V
(Chip)		(Note5)	T _{vi} =150 °C	-	4.35	-	
Cies	Input capacitance			-	-	60.0	
Coes	Output capacitance	V _{CE} =10 V, G-E short-circuited	V _{CE} =10 V, G-E short-circuited		-	5.0	nF
Cres	Reverse transfer capacitance	1		-	-	1.0	
Q _G	Gate charge	V _{CC} =600 V, I _C =400 A, V _{GE} =15 V		-	1.0	-	μC
t _{d(on)}	Turn-on delay time	.,		-	-	300	
tr	Rise time	V _{CC} =600 V, I _C =400 A, V _{GE} =±15 V,		-	-	100	ns
t _{d(off)}	Turn-off delay time			-	-	500	
t _f	Fall time	R _G =0 Ω, Inductive load		-	-	150	1
·		I _E =400 A, G-E short-circuited,	T _{vj} =25 °C	-	2.40	2.80	
$V_{\text{EC}}^{\ (\text{Note.1})}$		Refer to the figure of test circuit	T _{vi} =125 °C	-	2.55	-	V
(Terminal)		(Note5)	T _{vi} =150 °C	-	2.50	-	
	Emitter-collector voltage	I _E =400 A,	T _{vj} =25 °C	-	2.35	2.75	
$V_{\text{EC}} \ ^{\text{(Note.1)}}$		G-E short-circuited.	T _{vi} =125 °C	-	2.50	-	V
(Chip)		(Note5)	T _{vi} =150 °C	-	2.45	-	
t _{rr} (Note1)	Reverse recovery time	V _{CC} =600 V, I _E =400 A, V _{GE} =±15 V,	- 1	-	-	250	ns
Q _{rr} (Note1)	Reverse recovery charge	$R_G=0$ Ω , Inductive load		-	26	-	μC
Eon	Turn-on switching energy per pulse	V _{CC} =600 V, I _C =I _E =400 A,		-	10.0	-	·
E _{off}	Turn-off switching energy per pulse	V_{GE} =±15 V, R_{G} =0 Ω , T_{vi} =150 °C,		-	20.0	-	mJ
E _{rr} (Note1)	Reverse recovery energy per pulse	Inductive load		-	25.0	-	mJ
R _{CC'+EE'}	Internal lead resistance	Main terminals-chip, per switch, T _C =25 °C (Note4)		-	0.2	-	mΩ
r _g	Internal gate resistance	Per switch		-	0.8	-	Ω

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THERMAL RESISTANCE CHARACTERISTICS

Symbol	Item	Conditions	Limits			Unit
	item	Conditions	Min.	Тур.	Max.	ax. Unit
$R_{th(j-c)Q}$	Thermal resistance	Junction to case, per Inverter IGBT (Note4)	-	-	76	K/kW
$R_{th(j-c)D}$		Junction to case, per Inverter FWD (Note4)	-	-	140	N/KVV
$R_{th(c-s)}$	Contact thermal resistance	Case to heat sink, per 1 module, Thermal grease applied (Note4, 6, 8)	-	9	1	K/kW

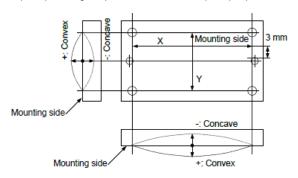
MECHANICAL CHARACTERISTICS

Symbol	Item	Conditions		Limits			I India
	item			Min.	Тур.	Max.	Unit
M _t	Mounting torque	Main terminals	M 6 screw	3.5	4.0	4.5	N·m
Ms	Mounting torque	Mounting to heat sink	M 6 screw	3.5	4.0	4.5	N·m
۵	Creepage distance	Terminal to terminal		17.0	-	-	- mm
ds		Terminal to base plate		42.6	-	-	
da	Classes	Terminal to terminal		11.0	-	-	m.m.
	Clearance	Terminal to base plate		28.1	-	-	mm
ec	Flatness of base plate	On the centerline X ,Y (Note7)		-50	-	+100	μm
m	mass	-		-	580	-	g

^{*.} This product is compliant with the Restriction of the Use of Certain Hazardous Substances in Electrical and Electronic Equipment (RoHS) directive 2011/65/EU and (EU)2015/863.

Note1. Represent ratings and characteristics of the anti-parallel, emitter-collector free-wheeling diode (FWD).

- 2. Junction temperature $(T_{\nu j})$ should not increase beyond $T_{\nu j\,m\,a\,x}$ rating.
- 3. Pulse width and repetition rate should be such that the device junction temperature (Tvj) dose not exceed Tvjmax rating.
- 4. Case temperature (T_C) and heat sink temperature (T_S) are defined on the each surface (mounting side) of base plate and heat sink just under the chips. Refer to the figure of chip location.
- 5. Pulse width and repetition rate should be such as to cause negligible temperature rise. Refer to the figure of test circuit.
- 6. Typical value is measured by using thermally conductive grease of λ =0.9 W/(m·K)/D_(C-S)=50 μ m.
- 7. The base plate (mounting side) flatness measurement point (X,Y) is as follows of the following figure.



Long term performance related to thermal conductive grease and PC-TIM (including but not limited to aspects such as the increase of thermal resistance

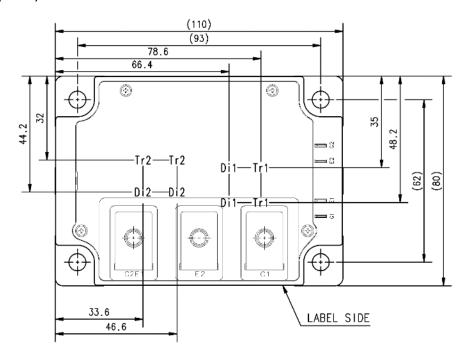
- 8. due to pumping out, etc.) should be verified under your specific application conditions. Each temperature condition (T_{vj max}, T_{vj op}, T_{C max}) must be maintained below the maximum rated temperature throughout consideration of the temperature rise even for long term usage.
- \divideontimes No short circuit capability is designed.

RECOMMENDED OPERATING CONDITIONS

Symbol	Itom	Conditions	Limits			Unit
	ltem		Min.	Тур.	Max.	Unit
Vcc	(DC) Supply voltage	Applied across C1-E2 terminals	-	600	850	V
V_{GEon}	Gate (-emitter drive) voltage	Applied across G1-Es1/G2-Es2 terminals	13.5	15.0	16.5	V
R _G	External gate resistance	Per switch	0	-	10	Ω
f _C	Switching frequency	V _{CC} =600 V, R _G =0 Ω, V _{GE} =±15 V,T _{vj} =150°C	-	-	60	kHz

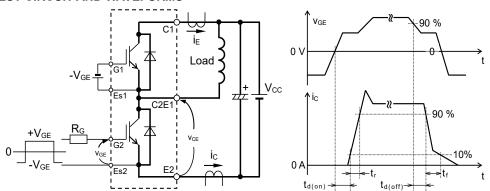
CHIP LOCATION (Top view)

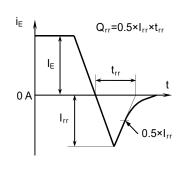
Dimension in mm, tolerance: ±1 mm



Tr1/Tr2: IGBT, Di1/Di2: FWD

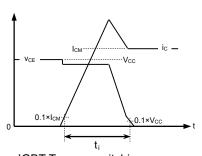
TEST CIRCUIT AND WAVEFORMS

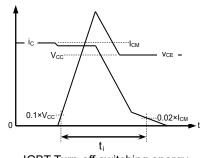


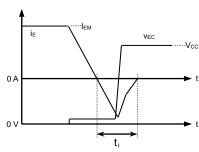


Switching characteristics test circuit and waveforms









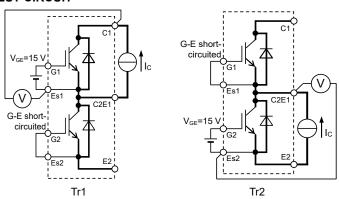
IGBT Turn-on switching energy

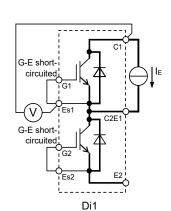
IGBT Turn-off switching energy

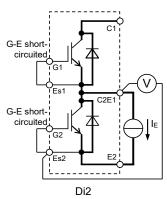
FWD Reverse recovery energy

Turn-on / Turn-off switching energy and Reverse recovery energy test waveforms (Integral time instruction drawing)

TEST CIRCUIT







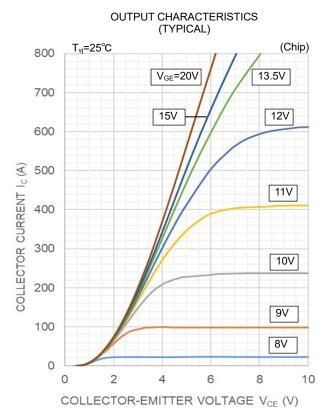
V_{CEsat} characteristics test circuit

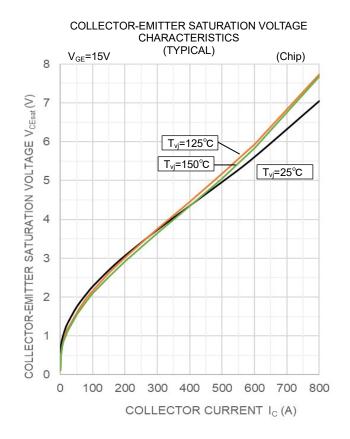
V_{EC} characteristics test circuit

CM400DU-24TH

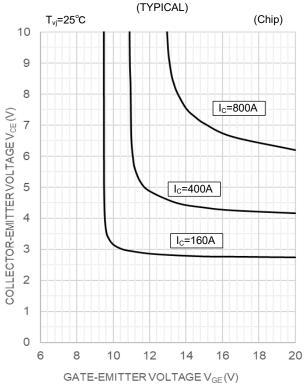
HIGH POWER SWITCHING USE INSULATED TYPE

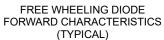
PERFORMANCE CURVES

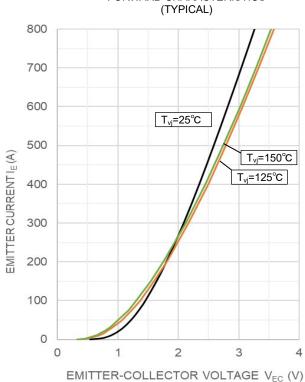




COLLECTOR-EMITTER VOLTAGECHARACTERISTICS

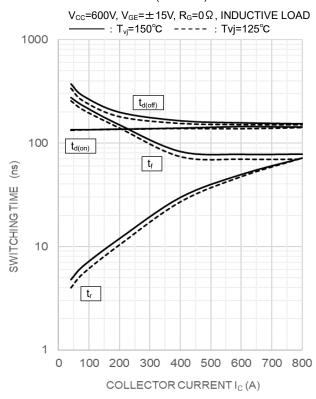






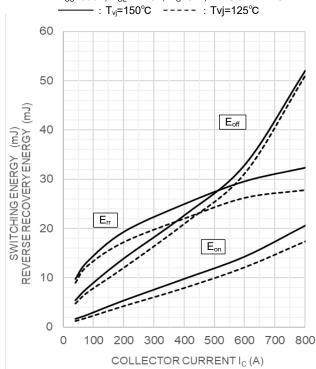
PERFORMANCE CURVES

HALF-BRIDGE SWITCHING CHARACTERISTICS (TYPICAL)



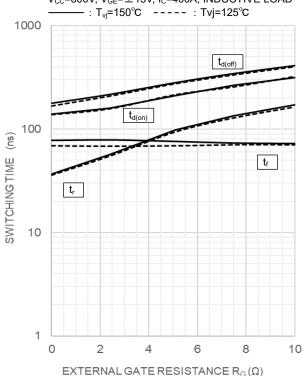
HALF-BRIDGE SWITCHING CHARACTERISTICS (TYPICAL)

 V_{CC} =600V, V_{GE} = \pm 15V, R_{G} =0 Ω , INDUCTIVE LOAD



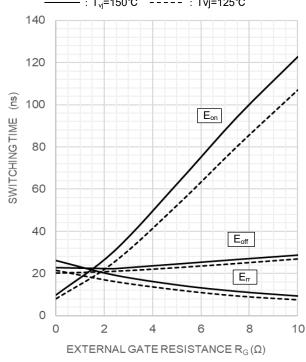
HALF-BRIDGE SWITCHING CHARACTERISTICS (TYPICAL)

 V_{CC} =600V, V_{GE} = \pm 15V, I_{C} =400A, INDUCTIVE LOAD

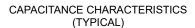


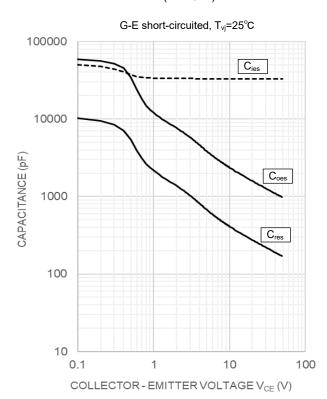
HALF-BRIDGE SWITCHING CHARACTERISTICS (TYPICAL)

 V_{CC} =600V, V_{GE} =±15V, I_{C} =400A, INDUCTIVE LOAD

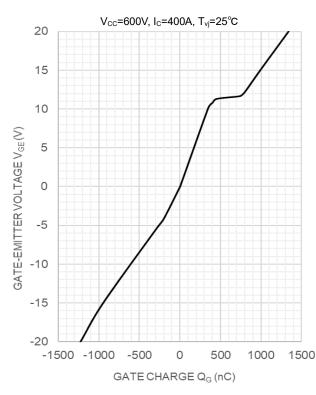


PERFORMANCE CURVES

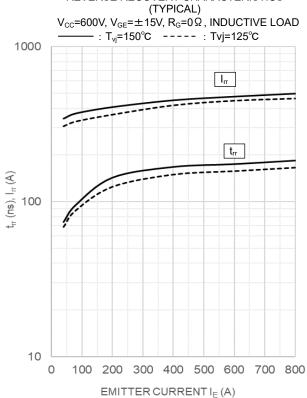




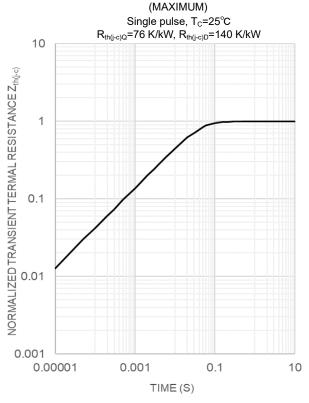
GATE CHARGE CHARACTERISTICS (TYPICAL)



FREE WHEELING DIODE REVERSE RECOVERY CHARACTERISTICS (TYPICAL)

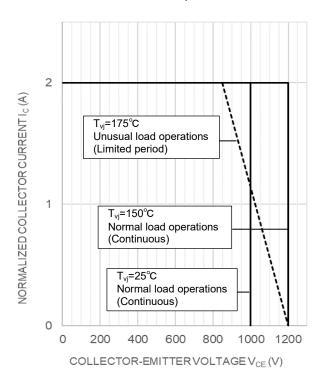


TRANSIENT THERMAL IMPEDANCE CHARACTERISTICS (MAXIMUM)



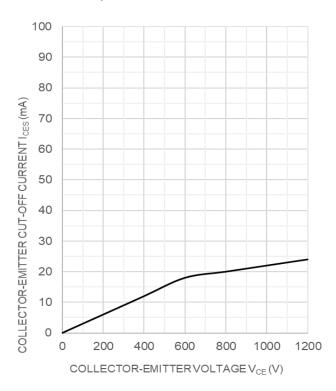
PERFORMANCE CURVES

TURN-OFF SWITCHING SAFE OPERATING AREA (REVERSE BIAS SAFE OPERATING AREA) (MAXIMUM) $V_{\text{CC}}\!=\!600\text{V, }I_{\text{C}}\!=\!400\text{A, }T_{\text{vj}}\!=\!25^{\circ}\!\text{C}$



COLLECTOR-EMITTER CUT-OFF CURRENT CHARACTRISTICS (TYPICAL)

 T_{vj} =150°C, G-E short-circuited



Note: The characteristics curves are presented for reference only and not guaranteed by production test, unless otherwise noted.

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